



Ref. Certif. No.

US-25228-UL

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST
CERTIFICATES FOR ELECTRICAL EQUIPMENT
(IECEE) CB SCHEMESYSTEME CEI D'ACCEPTATION MUTUELLE DE
CERTIFICATS D'ESSAIS DES EQUIPEMENTS
ELECTRIQUES (IECEE) METHODE OC

CB TEST CERTIFICATE

Product
ProduitName and address of the applicant
Nom et adresse du demandeurName and address of the manufacturer
Nom et adresse du fabricantName and address of the factory
Nom et adresse de l'usineNote: When more than one factory, please report on page 2
Note: Lorsque il y plus d'une usine, veuillez utiliser la 2^{ème} pageRatings and principal characteristics
Valeurs nominales et caractéristiques principalesTrademark (if any)
Marque de fabrique (si elle existe)Type of Manufacturer's Testing Laboratories used
Type de programme du laboratoire d'essais
constructeurModel / Type Ref.
Ref. De typeAdditional information (if necessary may also be
reported on page 2)
Les informations complémentaires (si nécessaire,,
peuvent être indiqués sur la 2^{ème} pageA sample of the product was tested and found
to be in conformity with
Un échantillon de ce produit a été essayé et a été
considéré conforme à laAs shown in the Test Report Ref. No. which forms part
of this Certificate
Comme indiqué dans le Rapport d'essais numéro de
référence qui constitue partie de ce Certificat

CERTIFICAT D'ESSAI OC

Component IC Current Limiter

Texas Instruments Inc
MS 8712 12500 TI BLVD
DALLAS, TX 75243 USATexas Instruments Inc
MS 8712 12500 TI BLVD
DALLAS, TX 75243 USATEXAS INSTRUMENTS DE MEXICO S DE R L DE C V
JESUS RIVERA FRANCO # 507 CD INDUSTRIAL 20290
AGUASCALIENTES AGS
MEXICO☒ Additional Information on page 2Input Voltage: 2.5 Vdc - 6.5 Vdc
Output Continuous Rating: 4.2 A
Output Current Limit: 5 A
Ambient: -40 to 85°CTPS255X, where x is 6 or 7, may be followed by Q, followed by
DRB, may be followed by R or T, may be followed by Q1.Additionally evaluated to EN 60950-1:2006/ A11:2009/ A1:2010/
A12:2011/ A2:2013; National Differences specified in the CB Test
Report.☐ Additional Information on page 2IEC 60950-1(ed.2), IEC 60950-1(ed.2);am1, IEC
60950-1(ed.2);am2

E169910-A27-CB-1 issued on 2015-05-25

This CB Test Certificate is issued by the National Certification Body
Ce Certificat d'essai OC est établi par l'Organisme **National de Certification**UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA
UL (Denko), Borupvang 5A DK-2750 Ballerup, DENMARK
UL (JP), Marunouchi Trust Tower Main Building 6F, 1-8-3 Marunouchi, Chiyoda-ku, Tokyo 100-0005, JAPAN
UL (CA), 7 Underwriters Road, Toronto, M1R 3B4 Ontario, CANADAFor full legal entity names see www.ul.com/ncbnames

Date: 2015-05-28

Signature:

Jolanta M. Wroblewska



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Model Details:

TPS255X , where x is 6 or 7, may be followed by Q, followed by DRB, may be followed by R or T, may be followed by Q1.

Factories:

TEXAS INSTRUMENTS SEMICONDUCTOR MANUFACTURING (CHENGDU) CO., LTD.
NO. 8-8 & NO.8-10, KEXIN RD WEST ZONE OF CHENGDU HI-TECH INDUSTRIAL DEVELOPMENT CHENGDU
SICHUAN
CHINA

TEXAS INSTRUMENTS TAIWAN LTD
142 HSIN NAN RD, SEC 1 CHUNG HO TAIPEI HSIEN 235
TAIWAN

ASE ASSEMBLY & TEST (SHANGHAI) LTD
#669 GUOSHOUJING RD ZHANGJIANG HI-TECH PARK PUDONG NEW AREA SHANGHAI 201203
CHINA

UTAC THAI LTD
WELGROW INDUSTRIAL ESTATE, 73 MOO5 BANGNA-TRAD (KM 38) RDA BANGPAKONG, T BANGSAMAK
CHACHOENGSAO 24180
THAILAND

NANTONG FUJITSU MICROELECTRONICS CO LTD
NO 288 CHONGCHUAN RD CHONGCHUAN DEVELOPMENT ZONE NANTONG JIANGSU 226006
CHINA

TEXAS INSTRUMENTS MALAYSIA SDN BHD
1 LORONG ENGGANG 33 AMPANG/ULU KLANG 54200 KUALA LUMPUR
MALAYSIA

HANA MICROELECTRONICS CO LTD (JIA XING)
18 HANA RD XINCHENG INDUSTRIAL PARK XIUZHOU DISTRICT JIAXING ZHEJIANG 314000
CHINA

TI (PHILIPPINES) INC
CLARK TI SPECIAL ECONOMIC ZONE CLARK FREEPORT ZONE ANGELES PAMPANGA
PHILIPPINES

HANA SEMICONDUCTOR (AYUTTHAYA) CO LTD
HI-TECH IND ESTATE AUTH OF THAILAND 100 MOO1, T BAAN-LEN, A BANG PA-INKM 59 ASIA RD AYUTTHAYA
13160
THAILAND

CARSEM SEMICONDUCTOR CO LTD
NO 88 WEST SHEN HU ROAD IN DISTRICT 2 SUZHOU INDUSTRIAL PARK JIANGSU 215021
CHINA

Additional information (if necessary)

Information complémentaire (si nécessaire)



☒ UL (US), 333 Pfingsten Rd IL 60062, Northbrook, USA

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